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## Author Index

Abd El-Maksoud, S.A., The influence of some Arylazobenzoyl acetonitrile derivatives on the behaviour of carbon steel in acidic media  
Ai, J., J. Xu, F. He, X. Xie and Z. Xu, XPS study on double glow plasma corrosion-resisting surface alloying layer  
Amalnerkar, D.P., see Venkateswara Rao, A.  
Asami, K., see Tsunekawa, J.  
Asomoza, R., see Kudriavtsev, Yu.  
Avilés, F., A.I. Oliva and J.A. Aznárez, Dynamical thermal model for thin metallic film-substrate system with resistive heating  
Aznárez, J.A., see Avilés, F.  
Bañuelos, J.G., see Crespo-Sosa, A.  
Ben Younes, O., M. Oueslati and B. Bessaïs, Anodisation-related structural variations of porous silicon nanostructures investigated by photoluminescence and Raman spectroscopy  
Bessaïs, B., see Ben Younes, O.  
Bhattacharya, A.K., see Wilkes, M.F.  
Cao, G., see Grujicic, M.  
Celis, J.-P., see Zhang, X.  
Cheang-Wong, J.-C., see Crespo-Sosa, A.  
Chen, R., see Yang, Y.  
Chigare, P.S., see Kawar, R.K.  
Cho, S.-H., see Kim, J.-N.  
Choi, K., S. Ghosh, J. Lim and C.M. Lee, Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma  
Costina, I., see Podgursky, V.  
Crespo-Sosa, A., M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos, High energy ion irradiation induced surface roughening in Ag and Cu films  
Das, N.C., see Sahoo, N.K.  
Desai, T.A., see Sharma, S.  
di Forte-Poisson, M.A., see Pécz, B.  
Ding, S.-J., D.W. Zhang, J.-T. Wang and W.W. Lee, Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film  
Dinhut, J.F., see Panicaud, B.

206 (2003) 129  
206 (2003) 230  
206 (2003) 262  
206 (2003) 1  
206 (2003) 187  
206 (2003) 336  
206 (2003) 336  
206 (2003) 178  
206 (2003) 37  
206 (2003) 37  
206 (2003) 12  
206 (2003) 167  
206 (2003) 110  
206 (2003) 178  
206 (2003) 20  
206 (2003) 90  
206 (2003) 119  
206 (2003) 355  
206 (2003) 29  
206 (2003) 178  
206 (2003) 271  
206 (2003) 218  
206 (2003) 8  
206 (2003) 321  
206 (2003) 149  
Do, D.D., see Kowalczyk, P. 206 (2003) 67  
Duś, R., see Kobiela, T. 206 (2003) 78  
Eason, R.W., see Mailis, S. 206 (2003) 46  
Edelbro, R., Å. Sandström and J. Paul, Full potential calculations on the electron band-structures of Sphalerite, Pyrite and Chalcopyrite 206 (2003) 300  
Fouad, O.A., M. Yamazato, H. Ichinose and M. Nagano, Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties 206 (2003) 159  
Foulani, A., Electronic behaviour and field emission of metal-semiconductor-insulator-metal (MSIM) heterostructures based on a-C:H films 206 (2003) 294  
Franchy, R., see Podgursky, V. 206 (2003) 29  
Gailhanou, M., see Panicaud, B. 206 (2003) 149  
Gauden, P.A., see Kowalczyk, P. 206 (2003) 67  
Gersten, B., see Grujicic, M. 206 (2003) 167  
Ghosh, S., see Choi, K. 206 (2003) 355  
Gigandet, M.P., see Moutarlier, V. 206 (2003) 237  
Godines, A., see Kudriavtsev, Yu. 206 (2003) 187  
Grosseau-Poussard, J.L., see Panicaud, B. 206 (2003) 149  
Grujicic, M., G. Cao and B. Gersten, Enhancement of field emission in carbon nanotubes through adsorption of polar molecules 206 (2003) 167  
Gun'ko, V.M., see Kowalczyk, P. 206 (2003) 67  
Hayden, P., see Wilkes, M.F. 206 (2003) 12  
He, F., see Ai, J. 206 (2003) 230  
Hiraoka, A., see Iida, S. 206 (2003) 60  
Ichinose, H., see Fouad, O.A. 206 (2003) 159  
Iida, S., A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa, Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag 206 (2003) 60  
Jiang, Q., M. Zhao and J.C. Li, Formation of monoatomic chains of metallic elements 206 (2003) 331  
Johnson, R.W., see Sharma, S. 206 (2003) 218  
Kakita, T., see Tsuji, T. 206 (2003) 314  
Kang, K., see Tsunekawa, J. 206 (2003) 1  
Kawar, R.K., P.S. Chigare and P.S. Patil, Substrate temperature dependent structural,

- optical and electrical properties of spray deposited iridium oxide thin films  
Kim, D.-H., see Kim, J.-N.
- Kim, J.-N., K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho, Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS  
Kasuya, A., see Tsunekawa, J.  
Kawazoe, Y., see Tsunekawa, J.  
Kim, N.-K., see Kim, J.-N.  
Kobiela, T., B. Nowakowski and R. Duś, The influence of gas phase composition on the process of Au-Hg amalgam formation  
Kowalczyk, P., V.M. Gun'ko, A.P. Terzyk, P.A. Gauden, H. Rong, Z. Ryu and D.D. Do, The comparative characterization of structural heterogeneity of mesoporous activated carbon fibers (ACFs)  
Kudriavtsev, Yu., A. Villegas, A. Godines and R. Asomoza, Emission of CsM<sup>+</sup> clusters  
Kulkarni, M.M., see Venkateswara Rao, A.  
Kumar, S., V.S. Raju and T.R.N. Kutty, Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy  
Kutty, T.R.N., see Kumar, S.  
Kuzmin, M., see Laukkonen, P.
- Laukkonen, P., M. Kuzmin, R.E. Perälä, R.-L. Vaara and I.J. Väyrynen, Scanning tunneling microscopy study of GaAs(1 0 0) surface prepared by HCl-isopropanol treatment  
Lee, C.M., see Choi, K.  
Lee, S.Y., N. Mettlach, N. Nguyen, Y.M. Sun and J.M. White, Copper oxide reduction through vacuum annealing  
Lee, W.W., see Ding, S.-J.  
Lei, T.-Q., see Lu, Y.-P.  
Li, J.C., see Jiang, Q.  
Li, M.-S., see Lu, Y.-P.  
Lifang, X., see Qi, S.  
Lim, J., see Choi, K.  
Lu, Y.-P., Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei, Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment
- Ma, Q., and R.A. Rosenberg, Angle-resolved X-ray photoelectron spectroscopy study of the oxides on Nb surfaces for superconducting r.f. cavity applications  
Mailis, S., C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason, Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals  
Mendes, M., and R. Vilar, Influence of the working atmosphere on the excimer laser ablation of Al<sub>2</sub>O<sub>3</sub>-TiC ceramics
- Mettlach, N., see Lee, S.Y.  
Mingren, S., see Qi, S.  
Moutarlier, V., M.P. Gigandet and J. Pagetti, Characterisation of pitting corrosion in sealed anodic films formed in sulphuric, sulphuric/molybdate and chromic media  
Muñoz, M., see Crespo-Sosa, A.
- Nagano, M., see Fouad, O.A.  
Nguyen, N., see Lee, S.Y.  
Noritake, H., see Iida, S.  
Nowakowski, B., see Kobiela, T.
- Oliva, A.I., see Avilés, F.  
Oliver, A., see Crespo-Sosa, A.  
Oueslati, M., see Ben Younes, O.
- Pagetti, J., see Moutarlier, V.  
Panicaud, B., J.L. Grosseau-Poussard, P.O. Renault, J.F. Dinhut, D. Thiaudiére and M. Gailhanou, Study of stress effects in the oxidation of phosphated  $\alpha$ -iron: in situ measurement by diffraction of synchrotron radiation  
Park, B.-O., see Kim, J.-N.  
Patil, P.S., see Kawar, R.K.  
Paul, J., see Edelbro, R.  
Pécz, B., L. Tóth, M.A. di Forte-Poisson and J. Vacas, Ti<sub>3</sub>SiC<sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC  
Perälä, R.E., see Laukkonen, P.  
Podgursky, V., I. Costina and R. Franchy, Ultra thin Al<sub>2</sub>O<sub>3</sub> films grown on Ni<sub>3</sub>Al(1 0 0)
- Qi, S., X. Lifang, M. Xinxin and S. Mingren, Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers
- Raju, V.S., see Kumar, S.  
Renault, P.O., see Panicaud, B.  
Riziotis, C., see Mailis, S.  
Rong, H., see Kowalczyk, P.  
Rosenberg, R.A., see Ma, Q.  
Ryu, Z., see Kowalczyk, P.
- Sahoo, N.K., S. Thakur, M. Senthilkumar and N.C. Das, Surface viscoelasticity studies of Gd<sub>2</sub>O<sub>3</sub>, SiO<sub>2</sub> optical thin films and multilayers using force modulation and force-distance scanning probe microscopy  
Sandström, Å., see Edelbro, R.  
Sániger, J.M., see Crespo-Sosa, A.  
Schade, W., see Sharma, A.K.  
Scott, J.G., see Mailis, S.  
Senthilkumar, M., see Sahoo, N.K.  
Seth, T., see Venkateswara Rao, A.  
Sharma, A.K., R.K. Thareja, U. Willer and W. Schade, Phase transformation in room temperature pulsed laser deposited TiO<sub>2</sub> thin films

- Sharma, S., R.W. Johnson and T.A. Desai, Ultra-thin poly(ethylene glycol) films for silicon-based microdevices 206 (2003) 218
- Shin, K.-S., see Kim, J.-N. 206 (2003) 119
- Smith, P.G.R., see Mailis, S. 206 (2003) 46
- Song, Y.-Z., see Lu, Y.-P. 206 (2003) 345
- Sun, Y.M., see Lee, S.Y. 206 (2003) 102
- Tanaka, R., see Iida, S. 206 (2003) 60
- Terzyk, A.P., see Kowalczyk, P. 206 (2003) 67
- Thakur, S., see Sahoo, N.K. 206 (2003) 271
- Thareja, R.K., see Sharma, A.K. 206 (2003) 137
- Thiaudière, D., see Panicaud, B. 206 (2003) 149
- Tóth, L., see Pécz, B. 206 (2003) 8
- Tsuji, M., see Tsuji, T. 206 (2003) 314
- Tsuji, T., T. Kakita and M. Tsuji, Preparation of nano-size particles of silver with femtosecond laser ablation in water 206 (2003) 314
- Tsunekawa, J. Kang, K. Asami, Y. Kawazoe and A. Kasuya, Corrigendum to "Size and time dependences of the valence states of Sn ions in amphoteric tin oxide nanoparticles" 206 (2003) 1
- Vaara, R.-L., see Laukkonen, P. 206 (2003) 2
- Vacas, J., see Pécz, B. 206 (2003) 8
- Väyrynen, I.J., see Laukkonen, P. 206 (2003) 2
- Venkateswara Rao, A. M.M. Kulkarni, D.P. Amalnerkar and T. Seth, Surface chemical modification of silica aerogels using various alkyl-alkoxy/chloro silanes 206 (2003) 262
- Vilar, R., see Mendes, M. 206 (2003) 196
- Villegas, A., see Kudriavtsev, Yu. 206 (2003) 187
- Wang, J.-T., see Ding, S.-J. 206 (2003) 321
- White, J.M., see Lee, S.Y. 206 (2003) 102
- Wilkes, M.F., P. Hayden and A.K. Bhattacharya, Surface segregation of lanthanum and cerium ions in ceria/lanthana solid solutions: comparison between experimental results and a statistical-mechanical model 206 (2003) 12
- Willer, U., see Sharma, A.K. 206 (2003) 137
- Wu, J., see Yang, Y. 206 (2003) 20
- Xie, X., see Ai, J. 206 (2003) 230
- Xinxin, M., see Qi, S. 206 (2003) 53
- Xu, J., see Ai, J. 206 (2003) 230
- Xu, Z., see Ai, J. 206 (2003) 230
- Yamazato, M., see Fouad, O.A. 206 (2003) 159
- Yang, W., see Yang, Y. 206 (2003) 20
- Yang, Y., J. Zhang, W. Yang, J. Wu and R. Chen, Adsorption properties for urokinase on local diatomite surface 206 (2003) 20
- Yukawa, M., see Iida, S. 206 (2003) 60
- Zhang, D.W., see Ding, S.-J. 206 (2003) 321
- Zhang, J., see Yang, Y. 206 (2003) 20
- Zhang, X., and J.-P. Celis, Nanotribology of MoS<sub>x</sub> coatings investigated by oscillating lateral force microscopy 206 (2003) 110
- Zhao, M., see Jiang, Q. 206 (2003) 331
- Zhu, R.-F., see Lu, Y.-P. 206 (2003) 345

## Subject Index

### Ablation

Influence of the working atmosphere on the excimer laser ablation of  $\text{Al}_2\text{O}_3$ –TiC ceramics, M. Mendes and R. Vilar

206 (2003) 196

### Alkali metals

Emission of  $\text{CsM}^+$  clusters, Yu. Kudriavtsev, A. Villegas, A. Godines and R. Asomoza

206 (2003) 187

### Alloys

The influence of gas phase composition on the process of Au–Hg amalgam formation, T. Kobiela, B. Nowakowski and R. Duś

206 (2003) 78

Changes in chemical behavior of thin film lead zirconate titanate during  $\text{Ar}^+$ -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

XPS study on double glow plasma corrosion-resistant surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu

206 (2003) 230

### Aluminium

$\text{Ti}_3\text{SiC}_2$  formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas

206 (2003) 8

Dynamical thermal model for thin metallic film–substrate system with resistive heating, F. Avilés, A.I. Oliva and J.A. Aznárez

206 (2003) 336

### Aluminium oxide

Influence of the working atmosphere on the excimer laser ablation of  $\text{Al}_2\text{O}_3$ –TiC ceramics, M. Mendes and R. Vilar

206 (2003) 196

### Annealing

$\text{Ti}_3\text{SiC}_2$  formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas

206 (2003) 8

Phase transformation in room temperature pulsed laser deposited  $\text{TiO}_2$  thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade

206 (2003) 137

### Antimony

Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty

206 (2003) 250

### Argon

Changes in chemical behavior of thin film lead zirconate titanate during  $\text{Ar}^+$ -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

### Atomic force microscopy

Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason

206 (2003) 46

The influence of gas phase composition on the process of Au–Hg amalgam formation, T. Kobiela, B. Nowakowski and R. Duś

206 (2003) 78

High energy ion irradiation induced surface roughening in Ag and Cu films, A. Crespo-Sosa, M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos

206 (2003) 178

Ultrathin poly(ethylene glycol) films for silicon-based microdevices, S. Sharma, R.W. Johnson and T.A. Desai

206 (2003) 218

Removal efficiency of organic contaminants on Si wafer by dry cleaning using  $\text{UV}/\text{O}_3$  and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

206 (2003) 355

***Auger electron spectroscopy***

Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren

206 (2003) 53

Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

Phase transformation in room temperature pulsed laser deposited TiO<sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade

Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

***Band structure***

Full potential calculations on the electron band-structures of Sphalerite, Pyrite and Chalcopyrite, R. Edelbro, Å. Sandström and J. Paul

206 (2003) 300

***Barium***

Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty

206 (2003) 250

***Calcium***

Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 345

***Carbide***

Influence of the working atmosphere on the excimer laser ablation of Al<sub>2</sub>O<sub>3</sub>-TiC ceramics, M. Mendes and R. Vilar

206 (2003) 196

***Carbon***

The comparative characterization of structural heterogeneity of mesoporous activated carbon fibers (ACFs), P. Kowalczyk, V.M. Gun'ko, A.P. Terzyk, P.A. Gauden, H. Rong, Z. Ryu and D.D. Do

206 (2003) 67

Enhancement of field emission in carbon nanotubes through adsorption of polar molecules, M. Grujicic, G. Cao and B. Gersten

206 (2003) 167

Electronic behaviour and field emission of metal-semiconductor-insulator-metal (MSIM) heterostructures based on a-C:H films, A. Foulani

206 (2003) 294

Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

206 (2003) 321

***Ceramics***

Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty

206 (2003) 250

***Cerium***

Surface segregation of lanthanum and cerium ions in ceria/lanthana solid solutions: comparison between experimental results and a statistical-mechanical model, M.F. Wilkes, P. Hayden and A.K. Bhattacharya

206 (2003) 12

***Characterisation***

Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

***Chemical vapour deposition***

Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano

206 (2003) 159

Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

206 (2003) 321

***Clusters***

Influence of the working atmosphere on the excimer laser ablation of Al<sub>2</sub>O<sub>3</sub>-TiC ceramics, M. Mendes and R. Vilar

206 (2003) 196

Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji

206 (2003) 314

*Computer simulations*

- Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren  
Emission of CsM<sup>+</sup> clusters, Yu. Kudriavtsev, A. Villegas, A. Godines and R. Asomoza

*Copper*

- High energy ion irradiation induced surface roughening in Ag and Cu films, A. Crespo-Sosa, M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos  
Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

*Copper Iron*

- Full potential calculations on the electron band-structures of Sphalerite, Pyrite and Chalcopyrite, R. Edelbro, Å. Sandström and J. Paul

*Corrosion*

- The influence of some Arylazobenzoyl acetonitrile derivatives on the behaviour of carbon steel in acidic media, S.A. Abd El-Maksoud  
XPS study on double glow plasma corrosion-resisting surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu

*Depth profiling*

- Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren  
Phase transformation in room temperature pulsed laser deposited TiO<sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade

*Doping effects*

- Investigations on the chemical states of sintered barium titanate by X-ray photoelectron

- 206 (2003) 53  
206 (2003) 187  
206 (2003) 178  
206 (2003) 321

- spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty

206 (2003) 250

*Electrical properties*

- Ti<sub>3</sub>SiC<sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas  
Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag, S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa  
Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil  
Electronic behaviour and field emission of metal-semiconductor-insulator-metal (MSIM) heterostructures based on a-C:H films, A. Foulani

- 206 (2003) 8  
206 (2003) 60  
206 (2003) 90  
206 (2003) 294

*Electron microscopy*

- Ti<sub>3</sub>SiC<sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas  
Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason  
Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag, S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa  
Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho  
Phase transformation in room temperature pulsed laser deposited TiO<sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade  
Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano  
XPS study on double glow plasma corrosion-resisting surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu  
Surface chemical modification of silica aerogels using various alkyl-alkoxy/chlorosilanes, A. Venkateswara Rao, M.M. Kulkarni, D.P. Amalnerkar and T. Seth  
Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji

- 206 (2003) 8  
206 (2003) 46  
206 (2003) 60  
206 (2003) 119  
206 (2003) 137  
206 (2003) 159  
206 (2003) 230  
206 (2003) 262  
206 (2003) 314

*Ellipsometry*

Ultrathin poly(ethylene glycol) films for silicon-based microdevices, S. Sharma, R.W. Johnson and T.A. Desai

206 (2003) 218

*Etching*

Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason

206 (2003) 46

*Evaporation*

$Ti_3SiC_2$  formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas

206 (2003) 8

Surface viscoelasticity studies of  $Gd_2O_3$ ,  $SiO_2$  optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

*Field emission*

Enhancement of field emission in carbon nanotubes through adsorption of polar molecules, M. Grujicic, G. Cao and B. Gersten  
Electronic behaviour and field emission of metal–semiconductor–insulator–metal (MSIM) heterostructures based on a-C:H films, A. Foulani

206 (2003) 167

206 (2003) 294

*Gadolinium*

Surface viscoelasticity studies of  $Gd_2O_3$ ,  $SiO_2$  optical thin films and multilayers using force modulation and force–distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

*Gallium Arsenide*

Scanning tunneling microscopy study of  $GaAs(1\bar{0}\bar{0})$  surface prepared by HCl-isopropanol treatment, P. Laukkanen, M. Kuzmin, R.E. Perälä, R.-L. Vaara and I.J. Väyrynen

206 (2003) 2

*Glass*

Dynamical thermal model for thin metallic film–substrate system with resistive heating, F. Avilés, A.I. Oliva and J.A. Aznárez

206 (2003) 336

*Gold*

The influence of gas phase composition on the process of Au–Hg amalgam formation, T. Kobiela, B. Nowakowski and R. Duś

206 (2003) 78

Dynamical thermal model for thin metallic film–substrate system with resistive heating, F. Avilés, A.I. Oliva and J.A. Aznárez

206 (2003) 336

*Heterostructures*

Electronic behaviour and field emission of metal–semiconductor–insulator–metal (MSIM) heterostructures based on a-C:H films, A. Foulani

206 (2003) 294

*Hydrogen*

Electron conduction mechanism of  $Si(1\bar{0}\bar{0})/Ag$  and  $Si(1\bar{0}\bar{0})/H/Ag$ , S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa

206 (2003) 60

Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 345

*Indium*

Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

*Infrared spectroscopy*

Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 345

Removal efficiency of organic contaminants on Si wafer by dry cleaning using  $UV/O_3$  and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

206 (2003) 355

*Ion bombardment*

Changes in chemical behavior of thin film lead zirconate titanate during  $Ar^+$ -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

High energy ion irradiation induced surface roughening in Ag and Cu films, A. Crespo-Sosa, M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos

206 (2003) 178

***Ion implantation***

Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren

206 (2003) 53

***Iron***

Study of stress effects in the oxidation of phosphated  $\alpha$ -iron: in situ measurement by diffraction of synchrotron radiation, B. Panicaud, J.L. Grosseau-Poussard, P.O. Renault, J.F. Dinhut, D. Thiaudiére and M. Gailhanou

206 (2003) 149

***Lanthanum***

Surface segregation of lanthanum and cerium ions in ceria/lanthana solid solutions: comparison between experimental results and a statistical-mechanical model, M.F. Wilkes, P. Hayden and A.K. Bhattacharya

206 (2003) 12

***Laser processing***

Influence of the working atmosphere on the excimer laser ablation of  $\text{Al}_2\text{O}_3$ -TiC ceramics, M. Mendes and R. Vilar  
Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji

206 (2003) 196

206 (2003) 314

***Lead***

Changes in chemical behavior of thin film lead zirconate titanate during  $\text{Ar}^+$ -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

***Lithium niobate***

Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason

206 (2003) 46

***Low energy electron diffraction***

Scanning tunneling microscopy study of  $\text{GaAs}(1\ 0\ 0)$  surface prepared by HCl-isopropanol treatment, P. Laukkonen, M. Kuzmin, R.E. Perälä, R.-L. Vaara and I.J. Väyrynen

206 (2003) 2

***Luminescence***

Anodisation-related structural variations of porous silicon nanostructures investigated by photoluminescence and Raman spectroscopy, O. Ben Younes, M. Oueslati and B. Bessaïs

206 (2003) 37

***Mercury***

The influence of gas phase composition on the process of Au-Hg amalgam formation, T. Kobiela, B. Nowakowski and R. Duś

206 (2003) 78

***Metals***

Formation of monoatomic chains of metallic elements, Q. Jiang, M. Zhao and J.C. Li  
Dynamical thermal model for thin metallic film-substrate system with resistive heating, F. Avilés, A.I. Oliva and J.A. Aznárez

206 (2003) 331

206 (2003) 336

***Molybdenum***

Nanotribology of  $\text{MoS}_x$  coatings investigated by oscillating lateral force microscopy, X. Zhang and J.-P. Celis

206 (2003) 110

***Multilayers***

Surface viscoelasticity studies of  $\text{Gd}_2\text{O}_3$ ,  $\text{SiO}_2$  optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

***Nanostructure***

Anodisation-related structural variations of porous silicon nanostructures investigated by photoluminescence and Raman spectroscopy, O. Ben Younes, M. Oueslati and B. Bessaïs

206 (2003) 37

***Nanostructures***

- Enhancement of field emission in carbon nanotubes through adsorption of polar molecules, M. Grujicic, G. Cao and B. Gersten  
Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji

206 (2003) 167  
206 (2003) 314

***Niobium***

- Angle-resolved X-ray photoelectron spectroscopy study of the oxides on Nb surfaces for superconducting r.f. cavity applications, Q. Ma and R.A. Rosenberg

206 (2003) 209

***Nitrogen silicon***

- Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren

206 (2003) 53

***Optical properties***

- Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

***Organic substances***

- Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

206 (2003) 355

***Oxides***

- Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

- Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

- Angle-resolved X-ray photoelectron spectroscopy study of the oxides on Nb surfaces for superconducting r.f. cavity applications, Q. Ma and R.A. Rosenberg

206 (2003) 209

- Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty

206 (2003) 250

- Surface viscoelasticity studies of Gd<sub>2</sub>O<sub>3</sub>, SiO<sub>2</sub> optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

- Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

206 (2003) 321

- Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 345

***Oxygen***

- Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

206 (2003) 355

***Ozone***

- Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

206 (2003) 355

***Phosphor***

- Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 345

***Photo chemistry***

- Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason

206 (2003) 46

***Photoelectron spectroscopy***

- Changes in chemical behavior of thin film lead zirconate titanate during Ar<sup>+</sup>-ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho

206 (2003) 119

- Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and

- film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano  
Angle-resolved X-ray photoelectron spectroscopy study of the oxides on Nb surfaces for superconducting r.f. cavity applications, Q. Ma and R.A. Rosenberg  
Ultrathin poly(ethylene glycol) films for silicon-based microdevices, S. Sharma, R.W. Johnson and T.A. Desai  
XPS study on double glow plasma corrosion-resistant surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu  
Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty  
Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

### Plasma processing

- Effect of plasma density on the distribution of incident ions and depth profile in plasma-based ion implanted layers, S. Qi, X. Lifang, M. Xinxin and S. Mingren  
Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano  
XPS study on double glow plasma corrosion-resistant surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu  
Factors influencing phase compositions and structure of plasma sprayed hydroxyapatite coatings during heat treatment, Y.-P. Lu, Y.-Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei  
Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

### Polymer

- Ultrathin poly(ethylene glycol) films for silicon-based microdevices, S. Sharma, R.W. Johnson and T.A. Desai

### Pulsed laser deposition

- Phase transformation in room temperature pulsed laser deposited TiO<sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade

206 (2003) 159

206 (2003) 209

206 (2003) 218

206 (2003) 230

206 (2003) 250

206 (2003) 321

206 (2003) 53

206 (2003) 159

206 (2003) 230

206 (2003) 345

206 (2003) 355

206 (2003) 218

206 (2003) 137

### Quantum effects

- Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag, S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa

206 (2003) 60

### Raman scattering

- Anodisation-related structural variations of porous silicon nanostructures investigated by photoluminescence and Raman spectroscopy, O. Ben Younes, M. Oueslati and B. Bessaïs

206 (2003) 37

- Continuous wave ultraviolet radiation induced frustration of etching in lithium niobate single crystals, S. Mailis, C. Riziotis, P.G.R. Smith, J.G. Scott and R.W. Eason

206 (2003) 46

- Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

### Scanning probe microscopy

- Nanotribology of MoS<sub>x</sub> coatings investigated by oscillating lateral force microscopy, X. Zhang and J.-P. Celis

206 (2003) 110

- Surface viscoelasticity studies of Gd<sub>2</sub>O<sub>3</sub>, SiO<sub>2</sub> optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

### Scanning Tunneling Microscopy

- Scanning tunneling microscopy study of GaAs(1 0 0) surface prepared by HCl-isopropanol treatment, P. Laukkanen, M. Kuzmin, R.E. Perälä, R.-L. Vaara and I.J. Väyrynen

206 (2003) 2

### Secondary ion mass spectroscopy

- Emission of CsM<sup>+</sup> clusters, Yu. Kudriavtsev, A. Villegas, A. Godines and R. Asomoza

206 (2003) 187

### Silane

- Surface chemical modification of silica aerogels using various alkyl-alkoxy/chlorosilanes, A. Venkateswara Rao, M.M. Kulkarni, D.P. Amalnerkar and T. Seth

206 (2003) 262

*Silicides*

Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano

206 (2003) 159

*Silicon*

Anodisation-related structural variations of porous silicon nanostructures investigated by photoluminescence and Raman spectroscopy, O. Ben Younes, M. Oueslati and B. Bessaïs

Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag, S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa

Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

Removal efficiency of organic contaminants on Si wafer by dry cleaning using UV/O<sub>3</sub> and ECR plasma, K. Choi, S. Ghosh, J. Lim and C.M. Lee

*Silicon carbide*

Ti<sub>3</sub>SiC<sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas

206 (2003) 8

*Silicon oxide*

Surface viscoelasticity studies of Gd<sub>2</sub>O<sub>3</sub>, SiO<sub>2</sub> optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das

206 (2003) 271

*Silver*

Electron conduction mechanism of Si(1 0 0)/Ag and Si(1 0 0)/H/Ag, S. Iida, A. Hiraoka, H. Noritake, R. Tanaka and M. Yukawa

High energy ion irradiation induced surface roughening in Ag and Cu films, A. Crespo-Sosa, M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos

Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji

206 (2003) 60

206 (2003) 178

206 (2003) 314

*Spray pyrolysis technique (SPT)*

Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil

206 (2003) 90

*Sputter deposition*

Chemical bonding of magnetron-sputtered copper on PECVD amorphous SiCOF film, S.-J. Ding, D.W. Zhang, J.-T. Wang and W.W. Lee

206 (2003) 321

*Sputtering*

Emission of CsM<sup>+</sup> clusters, Yu. Kudriavtsev, A. Villegas, A. Godines and R. Asomoza

206 (2003) 187

*Steel*

The influence of some Arylazobenzoyl acetonitrile derivatives on the behaviour of carbon steel in acidic media, S.A. Abd El-Maksoud

206 (2003) 129

XPS study on double glow plasma corrosion-resisting surface alloying layer, J. Ai, J. Xu, F. He, X. Xie and Z. Xu

206 (2003) 230

*Sulphades*

Full potential calculations on the electron band-structures of Sphalerite, Pyrite and Chalcopyrite, R. Edelbro, Å. Sandström and J. Paul

206 (2003) 300

*Sulphides*

Nanotribology of MoS<sub>x</sub> coatings investigated by oscillating lateral force microscopy, X. Zhang and J.-P. Celis

206 (2003) 110

*Superconductivity*

Angle-resolved X-ray photoelectron spectroscopy study of the oxides on Nb surfaces for superconducting r.f. cavity applications, Q. Ma and R.A. Rosenberg

206 (2003) 209

*Surface morphology*

Scanning tunneling microscopy study of GaAs(1 0 0) surface prepared by HCl-isopropanol treatment, P. Laukkanen, M. Kuz-

min, R.E. Perälä, R.-L. Vaara and I.J. Väyrynen	206 (2003) 2	<b>Titanium</b>
<b>Surface roughness</b>		Ti <sub>3</sub> SiC <sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas Changes in chemical behavior of thin film lead zirconate titanate during Ar <sup>+</sup> -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano Influence of the working atmosphere on the excimer laser ablation of Al <sub>2</sub> O <sub>3</sub> -TiC ceramics, M. Mendes and R. Vilar Investigations on the chemical states of sintered barium titanate by X-ray photoelectron spectroscopy, S. Kumar, V.S. Raju and T.R.N. Kutty
High energy ion irradiation induced surface roughening in Ag and Cu films, A. Crespo-Sosa, M. Muñoz, J.-C. Cheang-Wong, A. Oliver, J.M. Sániger and J.G. Bañuelos	206 (2003) 178	206 (2003) 8
<b>Surface segregation</b>		206 (2003) 119
Surface segregation of lanthanum and cerium ions in ceria/lanthana solid solutions: comparison between experimental results and a statistical-mechanical model, M.F. Wilkes, P. Hayden and A.K. Bhattacharya	206 (2003) 12	206 (2003) 159
<b>Surface thermodynamics</b>		206 (2003) 196
Surface segregation of lanthanum and cerium ions in ceria/lanthana solid solutions: comparison between experimental results and a statistical-mechanical model, M.F. Wilkes, P. Hayden and A.K. Bhattacharya	206 (2003) 12	206 (2003) 250
<b>Thin films</b>		<b>Titanium oxide</b>
Ti <sub>3</sub> SiC <sub>2</sub> formed in annealed Al/Ti contacts to p-type SiC, B. Pécz, L. Tóth, M.A. di Forte-Poisson and J. Vacas Changes in chemical behavior of thin film lead zirconate titanate during Ar <sup>+</sup> -ion bombardment using XPS, J.-N. Kim, K.-S. Shin, D.-H. Kim, B.-O. Park, N.-K. Kim and S.-H. Cho Phase transformation in room temperature pulsed laser deposited TiO <sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade Titanium disilicide formation by rf plasma enhanced chemical vapor deposition and film properties, O.A. Fouad, M. Yamazato, H. Ichinose and M. Nagano Ultrathin poly(ethylene glycol) films for silicon-based microdevices, S. Sharma, R.W. Johnson and T.A. Desai Surface viscoelasticity studies of Gd <sub>2</sub> O <sub>3</sub> , SiO <sub>2</sub> optical thin films and multilayers using force modulation and force-distance scanning probe microscopy, N.K. Sahoo, S. Thakur, M. Senthilkumar and N.C. Das Dynamical thermal model for thin metallic film-substrate system with resistive heating, F. Avilés, A.I. Oliva and J.A. Aznárez	206 (2003) 8	Phase transformation in room temperature pulsed laser deposited TiO <sub>2</sub> thin films, A.K. Sharma, R.K. Thareja, U. Willer and W. Schade Nanotribology of MoS <sub>x</sub> coatings investigated by oscillating lateral force microscopy, X. Zhang and J.-P. Celis
	206 (2003) 119	206 (2003) 137
	206 (2003) 137	206 (2003) 110
	206 (2003) 159	
	206 (2003) 218	
	206 (2003) 271	
	206 (2003) 336	
		<b>Water</b>
		Preparation of nano-size particles of silver with femtosecond laser ablation in water, T. Tsuji, T. Kakita and M. Tsuji
		206 (2003) 314
		<b>X-ray diffraction</b>
		The influence of gas phase composition on the process of Au-Hg amalgam formation, T. Kobiela, B. Nowakowski and R. Duś
		Substrate temperature dependent structural, optical and electrical properties of spray deposited iridium oxide thin films, R.K. Kawar, P.S. Chigare and P.S. Patil
		Phase transformation in room temperature pulsed laser deposited TiO <sub>2</sub> thin films,
		206 (2003) 78
		206 (2003) 90

A.K. Sharma, R.K. Thareja, U. Willer and  
W. Schade

Study of stress effects in the oxidation of  
phosphated  $\alpha$ -iron: in situ measurement  
by diffraction of synchrotron radiation, B.  
Panicaud, J.L. Grosseau-Poussard, P.O.  
Renault, J.F. Dinhut, D. Thiaudiére and  
M. Gailhanou

Chemical bonding of magnetron-sputtered cop-  
per on PECVD amorphous SiCOF film,  
S.-J. Ding, D.W. Zhang, J.-T. Wang and  
W.W. Lee

Factors influencing phase compositions and  
structure of plasma sprayed hydroxyapatite  
coatings during heat treatment, Y.-P. Lu, Y.-  
Z. Song, R.-F. Zhu, M.-S. Li and T.-Q. Lei

206 (2003) 137

206 (2003) 149

206 (2003) 321

206 (2003) 345

**Zinc**

Full potential calculations on the electron band-  
structures of Sphalerite, Pyrite and Chalco-  
pyrite, R. Edelbro, Å. Sandström and J. Paul

206 (2003) 300

**Zirconium**

Changes in chemical behavior of thin film lead  
zirconate titanate during Ar<sup>+</sup>-ion bombard-  
ment using XPS, J.-N. Kim, K.-S. Shin, D.-  
H. Kim, B.-O. Park, N.-K. Kim and S.-H.  
Cho

206 (2003) 119